

# TEMIC

Siliconix

## SUP/SUB60N06-14

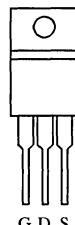
### N-Channel Enhancement-Mode Transistor

**175°C Maximum Junction Temperature**

#### Product Summary

V <sub>(BR)DSS</sub> (V)	r <sub>D(on)</sub> ( $\Omega$ )	I <sub>D</sub> (A)
60	0.014	60 <sup>a</sup>

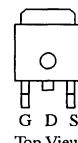
TO-220AB



Top View

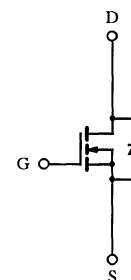
SUP60N06-14

TO-263



SUB60N06-14

Top View



N-Channel MOSFET

#### Absolute Maximum Ratings (T<sub>C</sub> = 25°C Unless Otherwise Noted)

Parameter		Symbol	Limit	Unit
Gate-Source Voltage		V <sub>GS</sub>	$\pm 20$	V
Continuous Drain Current (T <sub>J</sub> = 175°C)	T <sub>C</sub> = 25°C	I <sub>D</sub>	60 <sup>a</sup>	A
	T <sub>C</sub> = 100°C		42	
Pulsed Drain Current		I <sub>DM</sub>	240	
Avalanche Current		I <sub>AR</sub>	60	
Repetitive Avalanche Energy <sup>b</sup>	L = 0.1 mH	E <sub>AR</sub>	180	mJ
Power Dissipation	T <sub>C</sub> = 25°C (TO-220AB and TO-263)	P <sub>D</sub>	100	W
	T <sub>A</sub> = 25°C (TO-263) <sup>c</sup>		3.7	
Operating Junction and Storage Temperature Range		T <sub>J</sub> , T <sub>stg</sub>	-55 to 175	°C

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N/P-Channel  
MOSFETs

#### Thermal Resistance Ratings

Parameter		Symbol	Limit	Unit
Junction-to-Ambient	PCB Mount (TO-263) <sup>c</sup>	R <sub>thJA</sub>	40	°C/W
	Free Air (TO-220AB)		80	
Junction-to-Case		R <sub>thJC</sub>	1.5	

Notes:

a. Package limited.

b. Duty cycle ≤ 1%.

c. When mounted on 1" square PCB (FR-4 material).

(05/16/94)

**Advance Information**

6-161

Specifications ( $T_J = 25^\circ\text{C}$  Unless Otherwise Noted)

Parameter	Symbol	Test Condition	Min	Typ	Max	Unit
<b>Static</b>						
Drain-Source Breakdown Voltage	$V_{(\text{BR})\text{DSS}}$	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$	60			V
Gate Threshold Voltage	$V_{GS(\text{th})}$	$V_{DS} = V_{GS}, I_{DS} = 1 \text{ mA}$	2.0	3.0	4.0	
Gate-Body Leakage	$I_{GSS}$	$V_{DS} = 0 \text{ V}, V_{GS} = \pm 20 \text{ V}$			$\pm 100$	$\text{nA}$
Zero Gate Voltage Drain Current	$I_{DS}$	$V_{DS} = 48 \text{ V}, V_{GS} = 0 \text{ V}$		25		$\mu\text{A}$
		$V_{DS} = 48 \text{ V}, V_{GS} = 0 \text{ V}, T_J = 125^\circ\text{C}$			250	
		$V_{DS} = 48 \text{ V}, V_{GS} = 0 \text{ V}, T_J = 175^\circ\text{C}$			500	
On-State Drain Current <sup>b</sup>	$I_{D(\text{on})}$	$V_{DS} = 5 \text{ V}, V_{GS} = 10 \text{ V}$	60			A
Drain-Source On-State Resistance <sup>b</sup>	$r_{DS(\text{on})}$	$V_{GS} = 10 \text{ V}, I_D = 30 \text{ A}$			0.014	$\Omega$
		$V_{GS} = 10 \text{ V}, I_D = 30 \text{ A}, T_J = 125^\circ\text{C}$			0.023	
		$V_{GS} = 10 \text{ V}, I_D = 30 \text{ A}, T_J = 175^\circ\text{C}$			0.028	
Forward Transconductance <sup>b</sup>	$g_{fs}$	$V_{DS} = 15 \text{ V}, I_D = 30 \text{ A}$		TBD		S
<b>Dynamic<sup>a</sup></b>						
Input Capacitance	$C_{iss}$	$V_{GS} = 0 \text{ V}, V_{DS} = 25 \text{ V}, f = 1 \text{ MHz}$		TBD		$\text{pF}$
Output Capacitance	$C_{oss}$			TBD		
Reversen Transfer Capacitance	$C_{rss}$			TBD		
Total Gate Charge <sup>c</sup>	$Q_g$	$V_{DS} = 30 \text{ V}, V_{GS} = 10 \text{ V}, I_D = 60 \text{ A}$		TBD	130	$\text{nC}$
Gate-Source Charge <sup>c</sup>	$Q_{gs}$			TBD		
Gate-Drain Charge <sup>c</sup>	$Q_{gd}$			TBD		
Turn-On Delay Time <sup>c</sup>	$t_{d(\text{on})}$	$V_{DD} = 30 \text{ V}, R_L = 0.47 \Omega$ $I_D = 60 \text{ A}, V_{GEN} = 10 \text{ V}, R_G = 2.5 \Omega$		TBD	30	$\text{ns}$
Rise Time <sup>c</sup>	$t_r$			TBD	180	
Turn-Off Delay Time <sup>c</sup>	$t_{d(\text{off})}$			TBD	100	
Fall Time <sup>c</sup>	$t_f$			TBD	50	
<b>Source-Drain Diode Ratings and Characteristics (<math>T_C = 25^\circ\text{C}</math>)<sup>a</sup></b>						
Continuous Current	$I_s$				60	$\text{A}$
Pulsed Current	$I_{SM}$				240	
Forward Voltage <sup>b</sup>	$V_{SD}$	$I_F = 60 \text{ A}, V_{GS} = 0 \text{ V}$			1.8	V
Reverse Recovery Time	$t_{rr}$	$I_F = 60 \text{ A}, dI/dt = 100 \text{ A}/\mu\text{s}$		TBD		$\text{ns}$
Peak Reverse Recovery Current	$I_{RM(\text{REC})}$			TBD		
Reverse Recovery Charge	$Q_{rr}$			TBD		$\mu\text{C}$

Notes:

a. Guaranteed by design, not subject to production testing.

b. Pulse test; pulse width  $\leq 300 \mu\text{s}$ , duty cycle  $\leq 2\%$ .

c. Independent of operating temperature.